

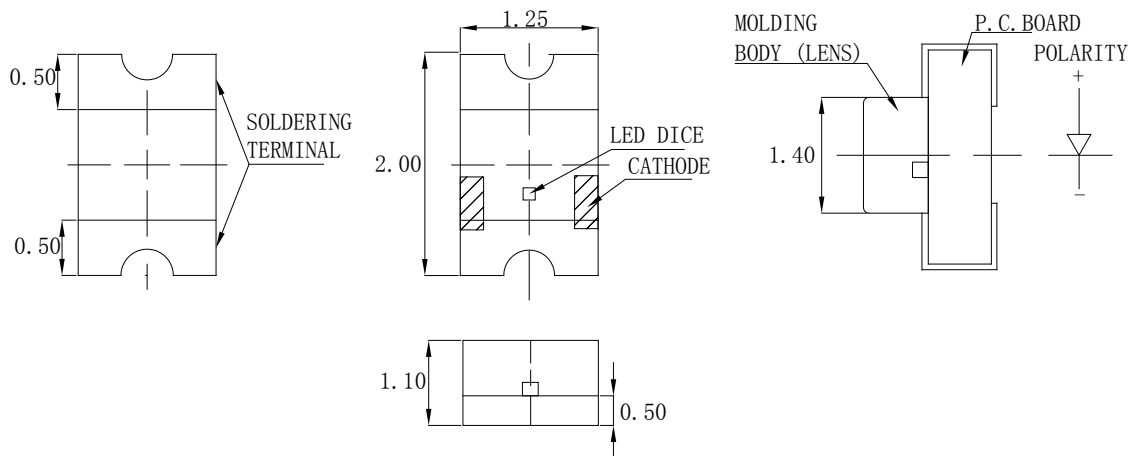
**Features**

- 2.0mm\*1.25mm SMT LED, Super thin (1.10H mm)
- Low Power Consumption
- Wide Viewing Angle
- Various Colors
- Compatible with automatic placement equipment.
- Compatible with infrared and vapor phase reflow and wave solder process.
- Meet ROHS Green Product.
- Package: 3000pcs/Reel

**Applications**

- Backlight and Indicator

**Package Dimensions**



**Notes:**

1. All dimensions are in millimeters (inches).
2. Tolerance is  $\pm 0.2\text{mm} (.0079")$  unless otherwise noted.
3. Specifications are subject to change without notice
4. This drawing is only for reference, not as a basis for the actual structure.



**Selection Guide**

Part No	Lens Type	Dice	Emitted Color
FSL-20125110TB-FATNDS	Water Clear	InGaN	Blue

**Electrical / Optical Characteristics At Ta=25 °C**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Condition
Iv	Luminous Intensity	18	25		mcd	IF=20mA
2θ1/2	Viewing Angle		130		deg	IF=20mA
λ Peak	Peak Emission Wavelength		468		nm	IF=20mA
λ d	Dominant Wavelength	460	470	475	nm	IF=20mA
Δλ	Spectral Line Half-Width		25		nm	IF=20mA
VF	Forward Voltage		2.8		V	IF=20mA
IR	Reverse Current			10	μ A	VR 5V

Note:

1. θ1/2 is the angle from optical centerline where the luminous intensity is 1/2 optical centerline value

**Absolute Maximum Ratings At Ta=25°C**

Parameter	Blue	Unit
Power Dissipation	72	mW
Peak Forward Current[1]	100	mA
Continuous Forward Current	20	mA
Derating Linear From 25°C	0.25	mA/°C
Reverse Voltage	5	V
Electrostatic Discharge Threshold (HBM)	150	V
Operating Temperature Range	-20°C to + 80°C	
Storage Temperature Range	-30°C to + 100°C	
Soldering Condition	260°C For 5 Seconds	

Note:

1. 1/10DutyCycle, 0.1msPulseWidth

**Electrical Optical Characteristics Curves At Ta=25 °C**

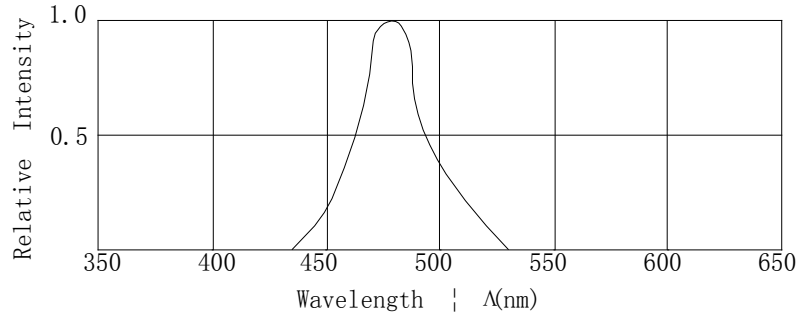


Fig.1 Relative Intensity VS. Wavelength

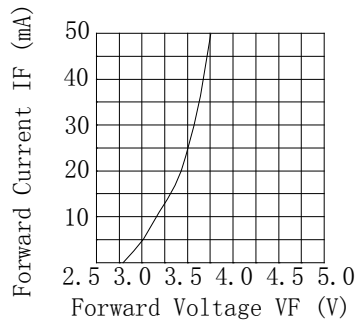


Fig.2 Forward Current vs. Forward Voltage

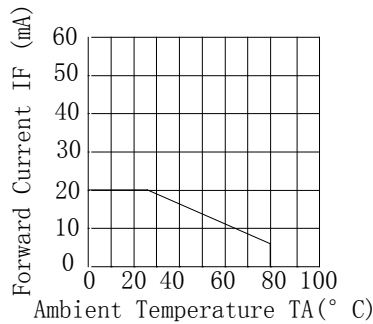


Fig.3 Forward Current Derating Curve

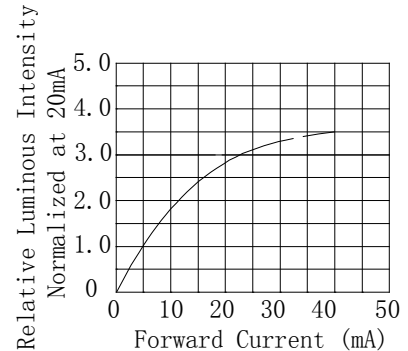


Fig.4 Relative Luminous Intensity vs. Forward Current

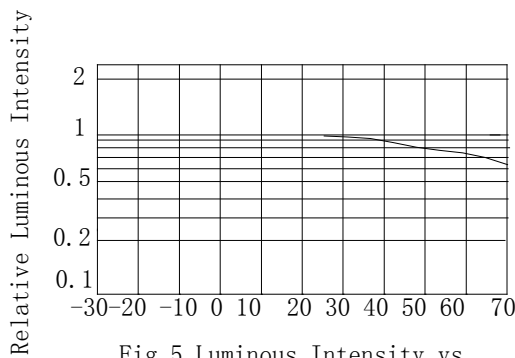


Fig.5 Luminous Intensity vs. Ambient Temperature

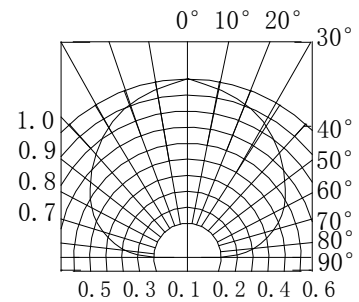


Fig.6 Spatial Distribution

**Bin Range Of Luminous Intensity**

Symbol	Bin Code	Min.	Max.	Unit	Condition
Iv	M	18	28	mcd	IF=20mA
	N	28	45		
	P	45	72		
	Q	72	112		
	R	112	180		
	S	180	288		

**Bin Range Of Forward Voltage**

Symbol	Bin Code	Min.	Max.	Unit	Condition
VF	V0	2.6	2.8	V	IF=20mA
	V1	2.8	3.0		
	V2	3.0	3.2		
	V3	3.2	3.4		
	V4	3.4	3.6		
	V5	3.6	3.8		

**Bin Range Of Dominate Wavelength**

Symbol	Bin Code	Min.	Max.	Unit	Condition
$\lambda d$	B	460	465	nm	IF=20mA
	C	465	470		
	D	470	475		

Notes:

1. Tolerance of Luminous Intensity +/-20%
2. Tolerance of Forward Voltage +/-0.2V
3. Tolerance of the Dominate Wavelength +/- 2nm



**Reliability Test Items Conditions**

Classification	Test Item	Test Conditions	Test hours	Result
Endurance Test	Operation Life	Connect with a power $I_F=20mA$ $T_a$ =Under room temperature	1000Hrs	0/20
	High Temperature High Humidity	$T_a=+65^{\circ}C \pm 5^{\circ}C$ RH=90%-95%	240Hrs	0/20
	High Temperature Storage	High $T_a=+85^{\circ}C \pm 5^{\circ}C$	1000Hrs	0/20
	Low Temperature Storage	Low $T_a=-35^{\circ}C \pm 5^{\circ}C$ Test time=1000hrs	1000Hrs	0/20
Environmental Test	Temperature Cycling	$-45^{\circ}C \sim +105^{\circ}C$ 15min 5min 15min	300 Cycles	0/20
	Thermal Shock	$-35^{\circ}C \sim \pm 5^{\circ}C \sim +85^{\circ}C \sim \pm 5^{\circ}C$ 5min 10sec 5min	300 Cycles	0/20
	Solder Resistance	Preheating: $120^{\circ}C - 150^{\circ}C$ , within 2 minutes. Operation heating : $260^{\circ}C$ (Max.), within 5 seconds (Max.)	5Cycles	0/20

**Judgment criteria of failure for the reliability**

Measuring items	Symbol	Measuring conditions	Judgment criteria for failure
Forward voltage	$V_F(V)$	$I_F=20mA$	Over $U \times 1.2$
Reverse current	$I_R(\mu A)$	$V_R=5V$	Over $U \times 2$
Luminous intensity	$I_v(mcd)$	$I_F=20mA$	Below $S \times 0.5$

Note: 1.U means the upper limit of specified characteristics. S means initial value.

2.Measurment shall be taken between 2 hours after the test pieces have been returned to normal ambient conditions after completion of each test.